CSPEMI307A

4-Channel ESD/EMI Filter Array plus 4-Channel ESD Array for USB

Features

- Four channels of combined EMI/RFI filtering + ESD protection
- Four additional channels of ESD-only protection
- EMI/ESD channels provide greater than 32dB attenuation at 1GHz
- ±15kV ESD protection on all channels (IEC 61000-4-2 Level 4, contact discharge)
- \pm 30kV ESD protection on all channels (HBM)
- Chip Scale Package features extremely low lead inductance for optimum filter and ESD performance
- 15-bump, 2.960mm X 1.330mm footprint Chip Scale Package (CSP)
- Lead-free version available

Applications

- EMI filtering and ESD protection for both data and I/O ports
- Outer 4 channels provide ESD protection for USB lines and other I/O port applications
- Wireless Handsets
- Handheld PCs / PDAs
- MP3 Players
- Notebooks
- Desktop PCs

FILTER+ESDn* GND (Pins B1-B3) 1 of 4 EMI/RFI + ESD Channels.FILTER+ESDn* 1 of 4 ESD-only Channels

Electrical Schematic

* See Package/Pinout Diagram for expanded pin information

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Product Description

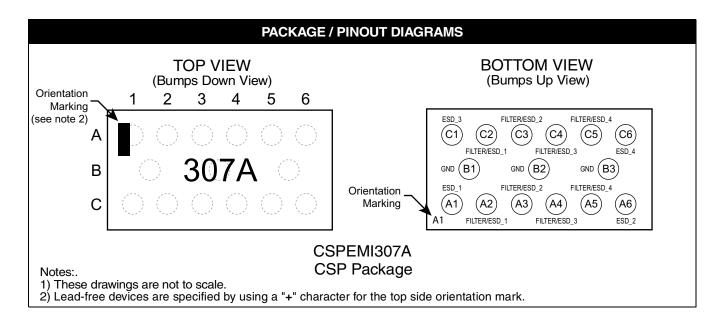
The CSPEMI307A is a multichannel EMI/ESD array offering a combination of four low-pass filter + ESD channels to reduce EMI/RFI emissions on a data port and four dedicated ESD-only channels intended specifically for ESD protection on a USB port. Each EMI/RFI channel integrates a high quality pi-style filter (C-R-C) which provides greater than 30dB attenuation in the 800-2700 MHz range. These pi-style filters support bidirectional filtering, controlling EMI both to and from a data port connector.

The CSPEMI307A provides a high-level of ESD protection on all eight channels for sensitive electronic components that may be subjected to electrostatic discharge (ESD). The input pins are designed and characterized to safely dissipate ESD strikes of 15kV, exceeding the maximum requirement of the IEC 61000-4-2 international standard. Using the MIL-STD-883 (Method 3015) specification for Human Body Model (HBM) ESD, the device provides protection for contact discharges to greater than 30kV.

The CSPEMI307A is particularly well suited for portable electronics (e.g., cellular telephones, PDAs, notebook computers) because of its small package footprint and low weight. The CSPEMI307A is available in a space-saving, low-profile Chip Scale Package with optional lead-free finishing.

1





		PIN DESCRIPTIONS
PIN(s)	NAME	DESCRIPTION
A1	ESD_1	ESD Channel 1
A2	FILTER+ESD_1	Filter + ESD Channel 1
A3	FILTER+ESD_2	Filter + ESD Channel 2
A4	FILTER+ESD_3	Filter + ESD Channel 3
A5	FILTER+ESD_4	Filter + ESD Channel 4
A6	ESD_2	ESD Channel 2
B1-B3	GND	Device Ground
C1	ESD_3	ESD Channel 3
C2	FILTER+ESD_1	Filter + ESD Channel 1
C3	FILTER+ESD_2	Filter + ESD Channel 2
C4	FILTER+ESD_3	Filter + ESD Channel 3
C5	FILTER+ESD_4	Filter + ESD Channel 4
C6	ESD_4	ESD Channel 4

Ordering Information

	PART NUMBERING INFORMATION					
		Standar	rd Finish	Lead-free Finish ²		
Bumps	Package	Ordering Part Number ¹	Part Marking	Ordering Part Number ¹	Part Marking	
15	CSP	CSPEMI307A	307A	CSPEMI307AG	307A	

Note 1: Parts are shipped in Tape & Reel form unless otherwise specified.

Note 2: Lead-free devices are specified by using a "+" character for the top side orientation mark.



Specifications

ABSOLUTE MAXIMUM RATINGS					
PARAMETER	RATING	UNITS			
Storage Temperature Range	-65 to +150	°C			
DC Power per Resistor	100	mW			
DC Package Power Rating	600	mW			

STANDARD OPERATING CONDITIONS						
PARAMETER	RATING	UNITS				
Operating Temperature Range	-40 to +85	°C				

	ELECTRICAL OPERATING CHARACTERISTICS ¹						
SYMBOL	PARAMETER	CONDITIONS	MIN	ТҮР	MAX	UNITS	
R	Resistance		80	100	120	Ω	
С	Capacitance	At 2.5V DC	24	30	36	pF	
TCR	Temperature Coefficient of Resistance			1200		ppm/°C	
TCC	Temperature Coefficient of Capacitance	At 2.5V DC		-300		ppm/°C	
V _{DIODE}	Diode Voltage (reverse bias)	I _{DIODE} =10μA	5.5			V	
I _{LEAK}	Diode Leakage Current (reverse bias)	V _{DIODE} =3.3V			100	nA	
V _{SIG}	Signal Voltage Positive Clamp Negative Clamp	I _{LOAD} = 10mA	5.6 -0.4	6.8 -0.8	9.0 -1.5	V V	
V _{ESD}	In-system ESD Withstand Voltage a) Human Body Model, MIL-STD-883, Method 3015 b) Contact Discharge per IEC 61000-4-2 Level 4	Notes 2,4 and 5	±30 ±15			kV kV	
V _{CL}	Clamping Voltage during ESD Discharge MIL-STD-883 (Method 3015), 8kV Positive Transients Negative Transients	Notes 2,3,4 and 5		+10 - 5		V V	
f _C	Cut-off frequency $Z_{SOURCE} = 50\Omega$, $Z_{LOAD} = 50\Omega$	R = 100Ω, C = 30pF		64		MHz	

Note 1: $T_A=25^{\circ}C$ unless otherwise specified.

Note 2: ESD applied to input and output pins with respect to GND, one at a time.

Note 3: Clamping voltage is measured at the opposite side of the EMI filter to the ESD pin. For example, if ESD is applied to Pin A2, then clamping voltage is measured at Pin C2.

Note 4: Unused pins are left open

Note 5: These parameters are guaranteed by design and characterization.

Performance Information

Typical Filter Performance (T_A=25°C, DC Bias=0V, 50 Ohm Environment)

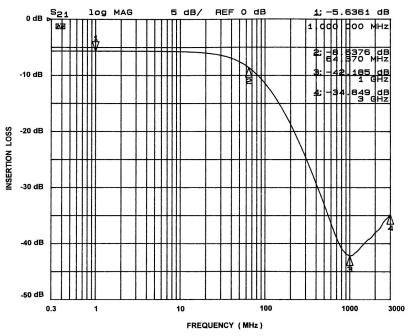


Figure 1. Insertion Loss VS. Frequency (A2-C2 to GND B2)

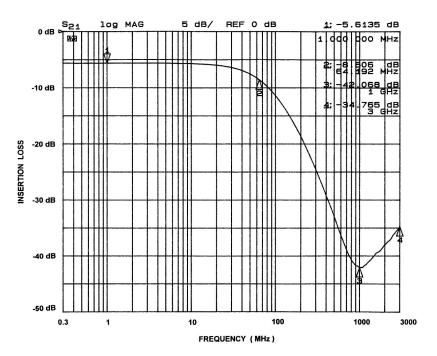


Figure 2. Insertion Loss VS. Frequency (A3-C3 to GND B2)

Performance Information

Typical Filter Performance (T_A=25°C, DC Bias=0V, 50 Ohm Environment)

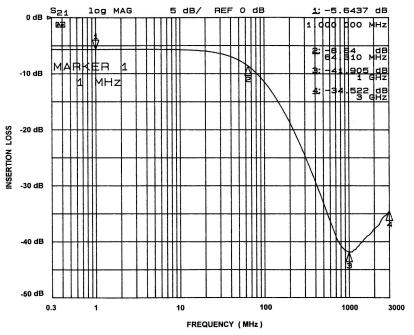


Figure 3. Insertion Loss VS. Frequency (A4-C4 to GND B2)

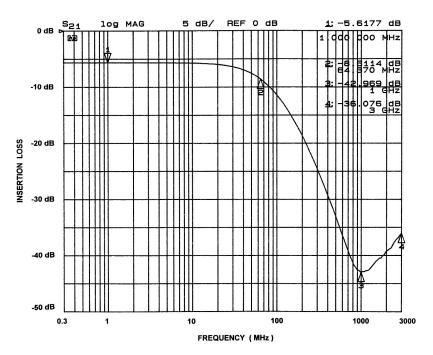


Figure 4. Insertion Loss VS. Frequency (A5-C5 to GND B2)

Performance Information

Typical Filter Performance (T_A=25°C, 50 Ohm Environment)

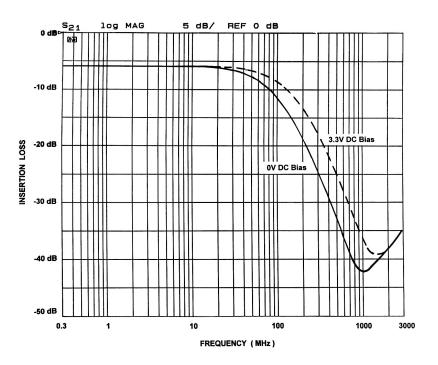


Figure 5. Comparison of Filter Response Curves for CSPEMI307A VS. DC Bias

Performance Information (cont'd)

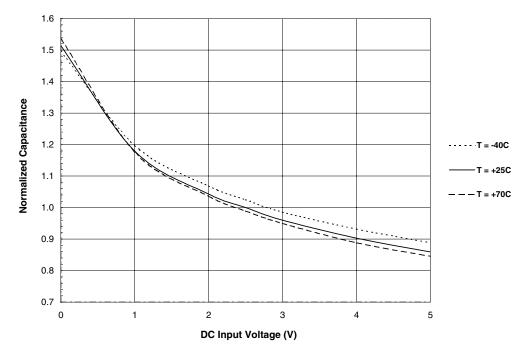
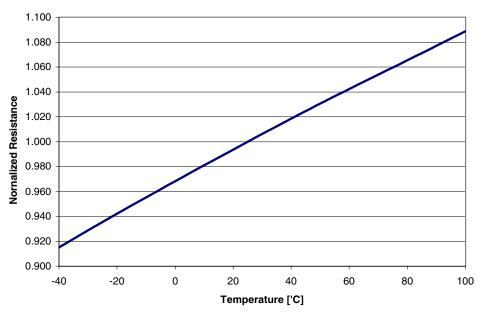
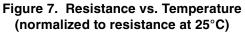


Figure 6. Filter Capacitance vs. Input Voltage over Temperature (normalized to capacitance at 2.5VDC and 25°C)



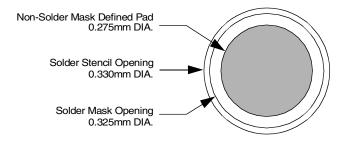




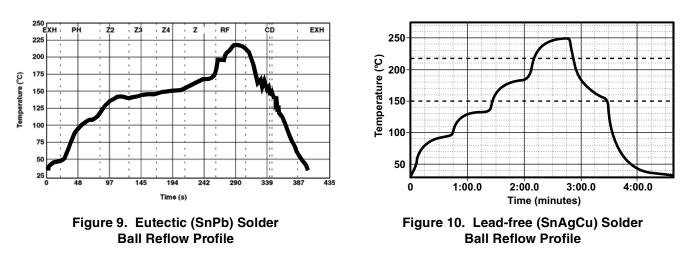
Application Information

Refer to Application Note AP-217, "The Chip Scale Package", for a detailed description of Chip Scale Packages offered by California Micro Devices.

PRINTED CIRCUIT BOARD RECOMMENDATIONS					
PARAMETER VALUE					
Pad Size on PCB	0.275mm				
Pad Shape	Round				
Pad Definition	Non-Solder Mask defined pads				
Solder Mask Opening	0.325mm Round				
Solder Stencil Thickness	0.125 - 0.150mm				
Solder Stencil Aperture Opening (laser cut, 5% tapered walls)	0.330mm Round				
Solder Flux Ratio	50/50 by volume				
Solder Paste Type	No Clean				
Pad Protective Finish	OSP (Entek Cu Plus 106A)				
Tolerance — Edge To Corner Ball	<u>+</u> 50μm				
Solder Ball Side Coplanarity	<u>+</u> 20μm				
Maximum Dwell Time Above Liquidous	60 seconds				
Soldering Maximum Temperature	260°C				







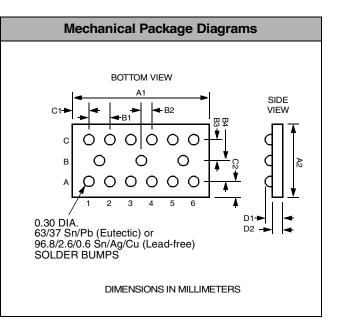


Mechanical Details

CSP Mechanical Specifications

CSPEMI307A devices are packaged in a custom Chip Scale Package (CSP). Dimensions are presented below. For complete information on CSP packaging, see the California Micro Devices CSP Package Information document.

PACKAGE DIMENSIONS							
Pack	age	Custom CSP					
Bum	nps			15			
Dim	Μ	lillimete	rs		Inches		
Dim	Min	Nom	Max	Min	Nom	Мах	
A1	2.915	2.960	3.005	0.1148	0.1165	0.1183	
A2	1.285	1.330	1.375	0.0506	0.0524	0.0541	
B1	0.495	0.500	0.500 0.505		0.0197	0.0199	
B2	0.245	0.250	0.255	0.0096	0.0098 0.0171	0.0100 0.0173	
B3	0.430	0.435	0.440	0.0169			
B4	0.430	0.435	0.435 0.440		0.0171	0.0173	
C1	0.180	0.230	0.280	0.0071	0.0091	0.0110	
C2	0.180	0.230	0.280	0.0071	0.0091	0.0110	
D1	0.561	0.605	0.605 0.649 0.		0.0238	0.0255	
D2	0.355	0.380	0.405	0.0140	0.0150	0.0159	
# per taj ree		3500 pieces					
	Controlling dimension: millimeters						



Package Dimensions for CSPEMI307A Chip Scale Package

CSP Tape and Reel Specifications

PART NUMBER	CHIP SIZE (mm)	POCKET SIZE (mm) B ₀ X A ₀ X K ₀	TAPE WIDTH W	REEL DIAMETER	QTY PER REEL	P ₀	P 1
CSPEMI307A	2.96 X 1.33 X 0.6	3.10 X 1.45 X 0.74	8mm	178mm (7")	3500	4mm	4mm

